Abstracts

Dynamic Diode Mixer Damage Measurements

R.V. Garver, C. Fazi and H. Bruns. "Dynamic Diode Mixer Damage Measurements." 1985 MTT-S International Microwave Symposium Digest 85.1 (1985 [MWSYM]): 535-536.

An experiemntal setup has been developed which permits the progressive degradation of a mixer to be observed while it is being exposed to high-power-microwave pulses at a low repetition rate.

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